

Dual N-Channel 30V(D-S) MOSFET

Product summary			
Symbol	Q1	Q2	Units
V_{DS}	30	30	V
$R_{DS(ON)}$ (at $V_{GS}=10V$) Typ.	6.8	3.5	$m\Omega$
$I_D(T_c=25^\circ C)$	43	80	A

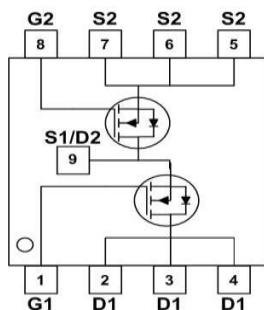
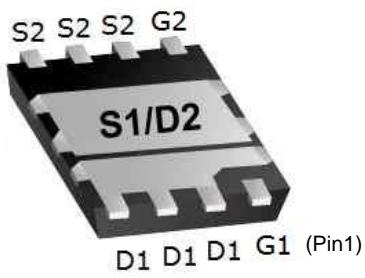
Features

- Advanced Trench Technology
- Low $R_{DS(ON)}$

Applications

- Load switching
- PWM Applications
- Power Management

Pin Configuration



Packing Information

Device	Package	Reel Size	Quantity(Min. Package)
ECAP43C03L	PDFN5X6-8L	13"	3000pcs

Absolute Maximum Ratings (at $T_A=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Q1	Q2	Units
V_{DS}	Drain-Source Voltage	30	30	V
V_{GS}	Gate-Source Voltage	± 20	± 20	V
I_D	Continuous Drain Current	$T_c=25^\circ C$	43	A
		$T_c=100^\circ C$	26	A
I_{DM}	Pulse Drain Current Tested ^A	160	320	A
E_{AS}	Single Pulse Avalanche Energy ^B	25	72	mJ
P_D	Power Dissipation	25	43	W
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to +150		°C

Thermal Characteristics

Symbol	Parameter	Typical	Units
$R_{eJC}(Q1)$	Thermal Resistance-Junction to case max	5.0	°C/W
$R_{eJC}(Q2)$	Thermal Resistance-Junction to case max	2.9	°C/W

Q1 Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Static Parameters						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_{\text{D}}=250\mu\text{A}$	30	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$	--	--	1	μA
I_{GSS}	Gate-Body Leakage Current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 20\text{V}$	--	--	± 100	nA
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.0	1.5	2.5	V
$\text{R}_{\text{DS(ON)}}$	Drain-Source On-State Resistance ^C	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$	--	6.8	9	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=15\text{A}$	--	10.3	14.5	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$	--	--	1.2	V
Dynamic Parameters ^D						
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}$ $f=1\text{MHz}$	--	1116	--	pF
C_{oss}	Output Capacitance		--	187	--	pF
C_{rss}	Reverse Transfer Capacitance		--	152	--	pF
Q_{g}	Total Gate Charge	$\text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=15\text{A}$ $\text{V}_{\text{GS}}=10\text{V}$	--	13.3	--	nC
Q_{gs}	Gate-Source Charge		--	3.1	--	nC
Q_{gd}	Gate-Drain Charge		--	5	--	nC
$t_{\text{D(on)}}$	Turn-on Delay Time	$\text{V}_{\text{DS}}=15\text{V}$ $, \text{R}_{\text{GEN}}=3\Omega,$ $\text{I}_{\text{D}}=30\text{A},$ $\text{V}_{\text{GS}}=10\text{V}$	--	15	--	ns
t_{r}	Turn-on Rise Time		--	19	--	ns
$t_{\text{D(off)}}$	Turn-off Delay Time		--	35	--	ns
t_{f}	Turn-off Fall Time		--	21	--	ns
t_{rr}	Reverse recovery time	$\text{I}_{\text{F}}=20\text{A},$ $\text{di}/\text{dt}=100 \text{ A}/\mu\text{s}$	--	14	--	ns
Q_{rr}	Reverse recovery charge		--	4.1	--	nC

A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

B. EAS condition: $T_J=25^\circ\text{C}$, $R_G=25\Omega$, $V_{DD}=25\text{V}$, $V_G=10\text{V}$, $L=0.5\text{mH}$, $I_{AS}=10\text{A}$.

C. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.

D. Guaranteed by design, not subject to production testing.

Q2 Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Static Parameters						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}$	--	--	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=\pm 20\text{V}$	--	--	± 100	nA
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.0	1.5	2.5	V
$R_{\text{DS}(\text{ON})}$	Drain-Source On-State Resistance ^C	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=30\text{A}$	--	3.5	4.2	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=20\text{A}$	--	4.6	6.0	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_{\text{S}}=30\text{A}, V_{\text{GS}}=0\text{V}$	--	--	1.2	V
Dynamic Parameters ^D						
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=15\text{V}$ $f=1\text{MHz}$	--	2680	--	pF
C_{oss}	Output Capacitance		--	393	--	pF
C_{rss}	Reverse Transfer Capacitance		--	330	--	pF
Q_g	Total Gate Charge	$V_{\text{DS}}=15\text{V}, I_{\text{D}}=30\text{A}$ $V_{\text{GS}}=10\text{V}$	--	30	--	nC
Q_{gs}	Gate-Source Charge		--	7.2	--	nC
Q_{gd}	Gate-Drain Charge		--	10.4	--	nC
$t_{\text{D}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=15\text{V}$ $, R_{\text{GEN}}=3\Omega,$ $I_{\text{D}}=30\text{A},$ $V_{\text{GS}}=10\text{V}$	--	23	--	ns
t_r	Turn-on Rise Time		--	28	--	ns
$t_{\text{D}(\text{off})}$	Turn-off Delay Time		--	74	--	ns
t_f	Turn-off Fall Time		--	36	--	ns
t_{rr}	Reverse recovery time	$I_F=20\text{A},$ $di/dt=100 \text{ A/uS}$	--	28	--	ns
Q_{rr}	Reverse recovery charge		--	21	--	nC

A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

B. EAS condition: $T_J=25^\circ\text{C}$, $V_{\text{DD}}=25\text{V}$, $V_G=10\text{V}$, $L=0.5\text{mH}$, $R_G=25\Omega$, $I_{\text{AS}}=17\text{A}$.

C. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.

D. Guaranteed by design, not subject to production testing.

Q1 Typical Characteristics

Figure 1: Output Characteristics

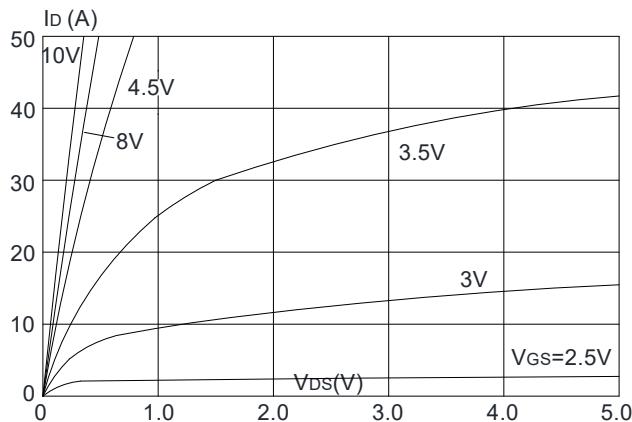


Figure 2: Typical Transfer Characteristics

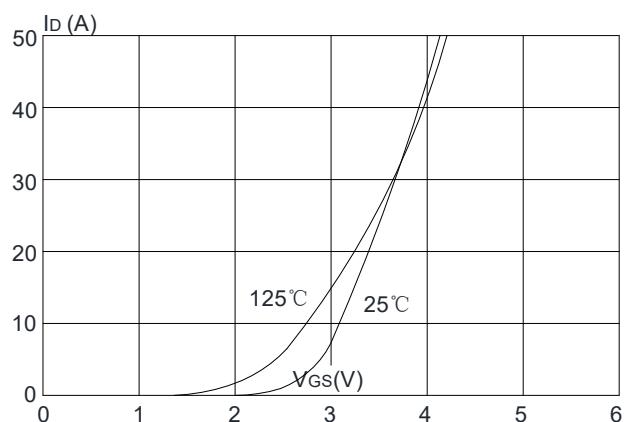


Figure 3: On-resistance vs. Drain Current

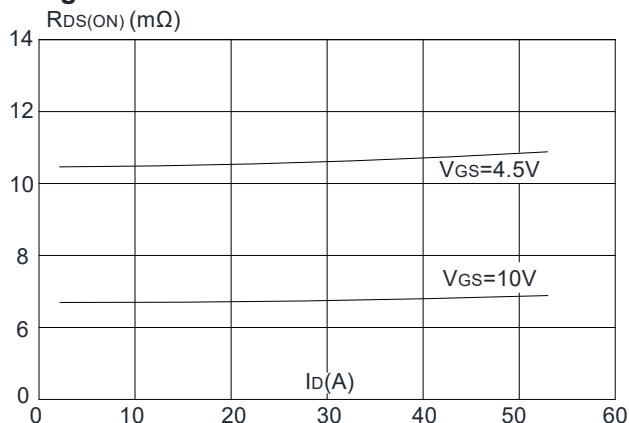


Figure 4: Body Diode Characteristics

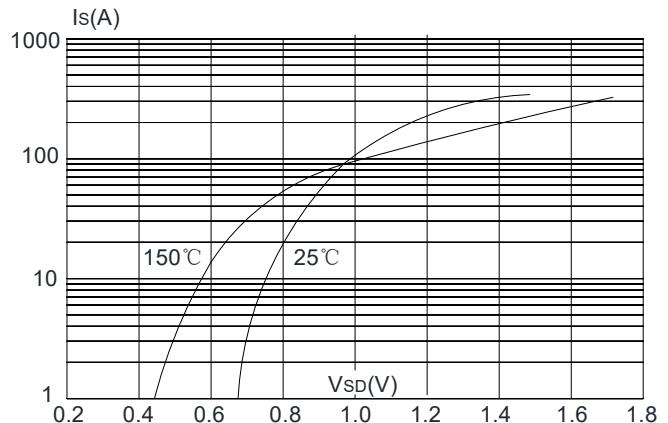


Figure 5: Gate Charge Characteristics

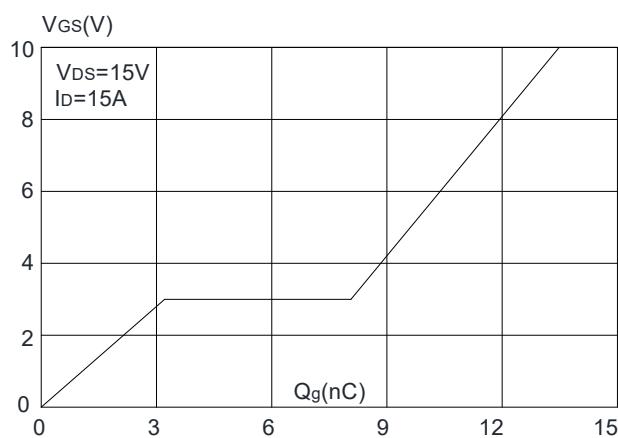
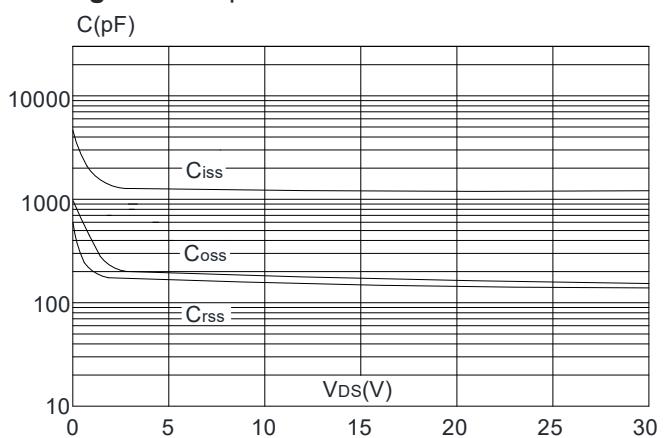


Figure 6: Capacitance Characteristics



Q1 Typical Characteristics

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

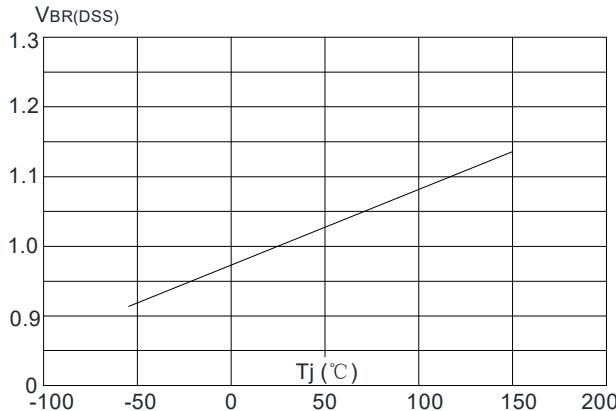


Figure 8: Normalized on Resistance vs. Junction Temperature

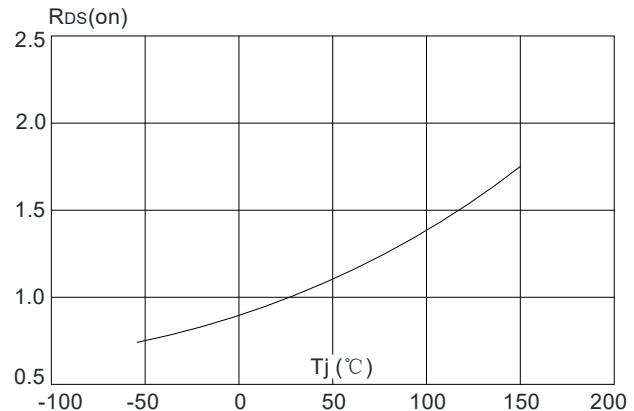


Figure 9: Maximum Safe Operating Area

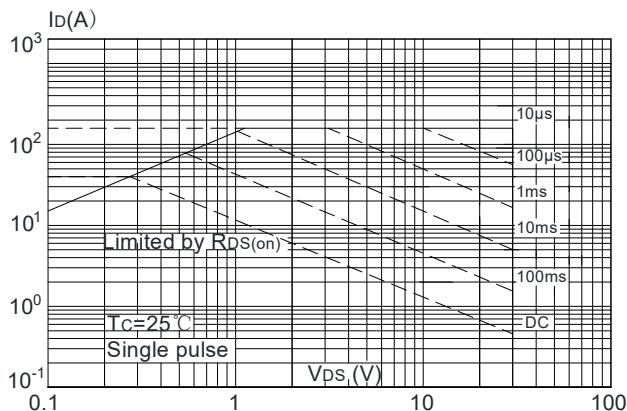


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

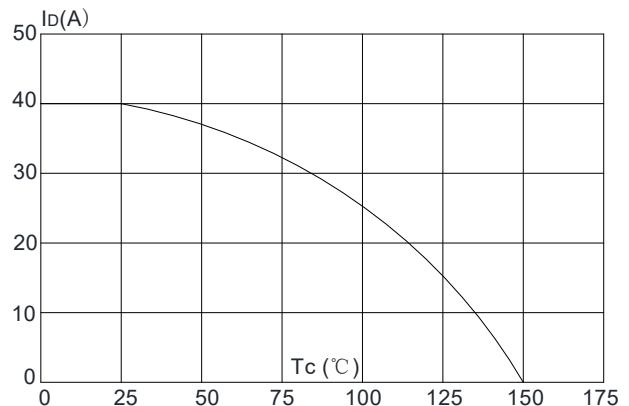
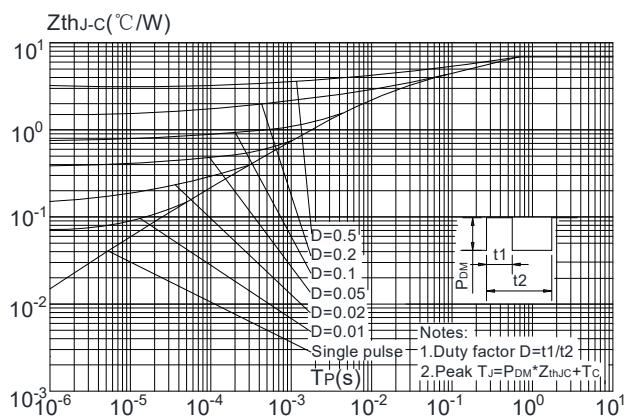


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



Q2 Typical Characteristics

Figure 1: Output Characteristics

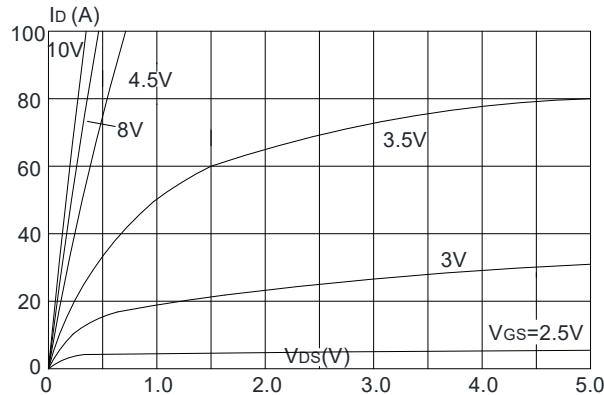


Figure 2: Typical Transfer Characteristics

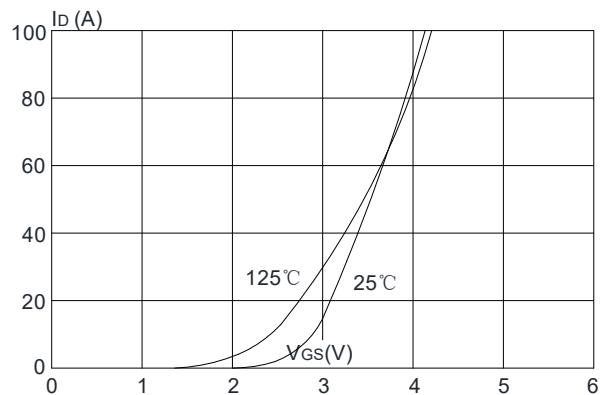


Figure 3: On-resistance vs. Drain Current

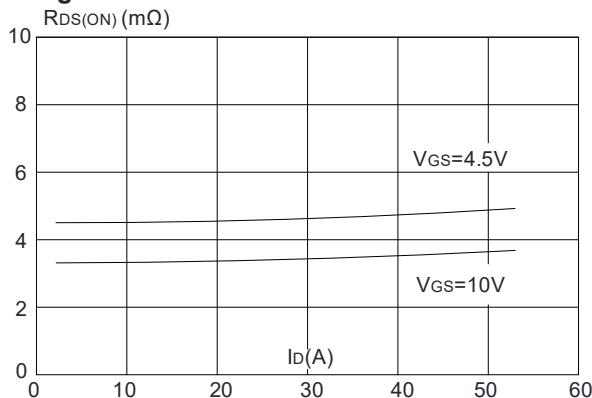


Figure 4: Body Diode Characteristics

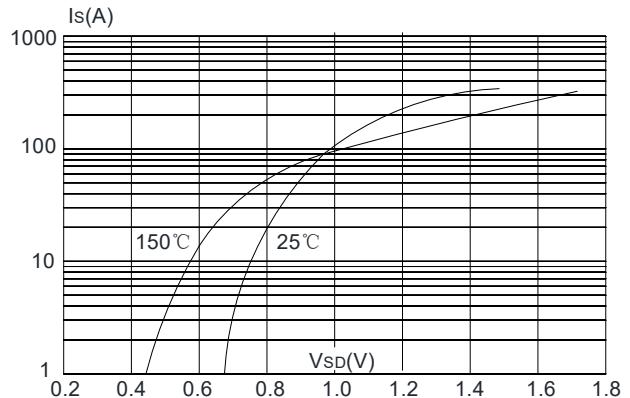


Figure 5: Gate Charge Characteristics

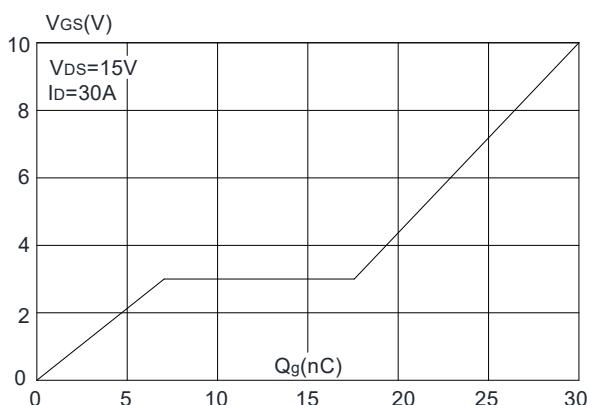
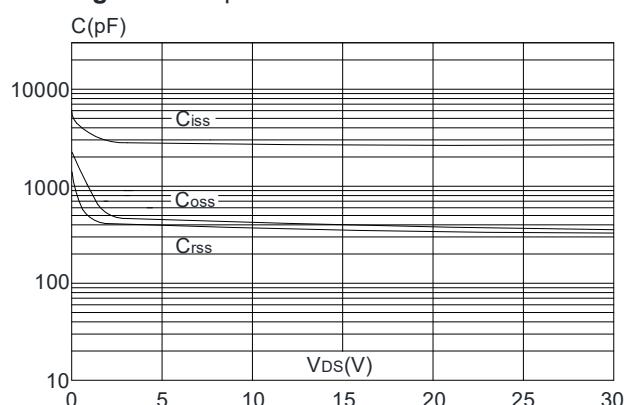


Figure 6: Capacitance Characteristics



Q2 Typical Characteristics

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

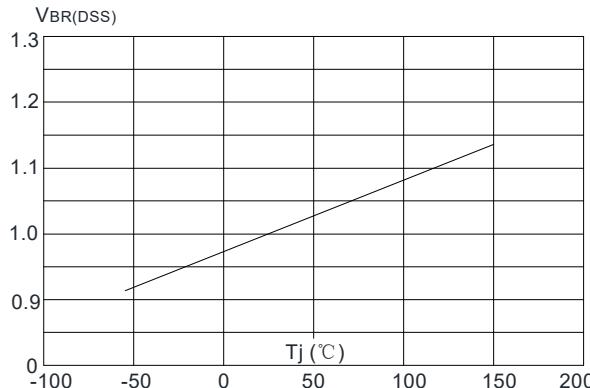


Figure 8: Normalized on Resistance vs. Junction Temperature

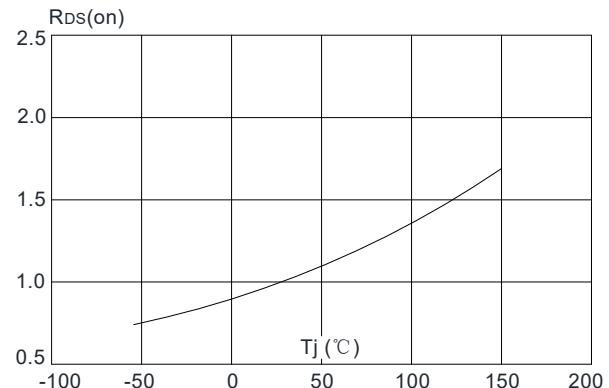


Figure 9: Maximum Safe Operating Area

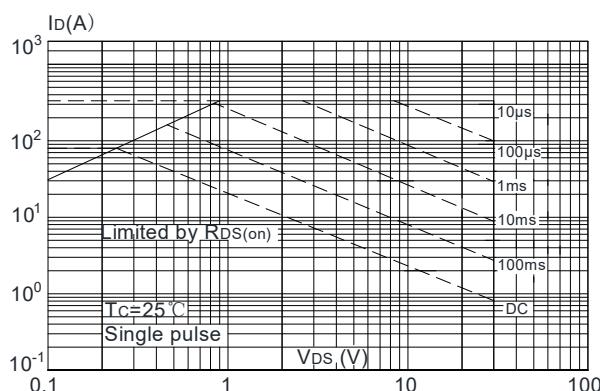


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

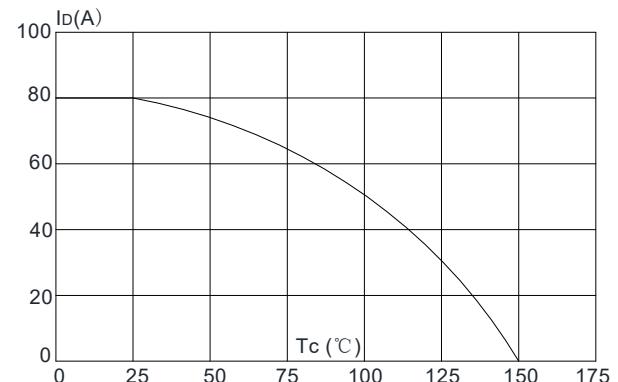
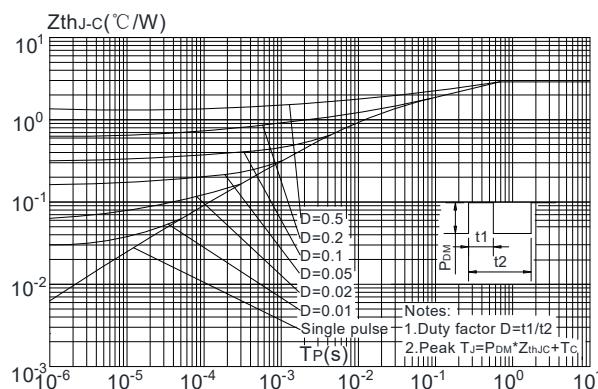


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



Test Circuit

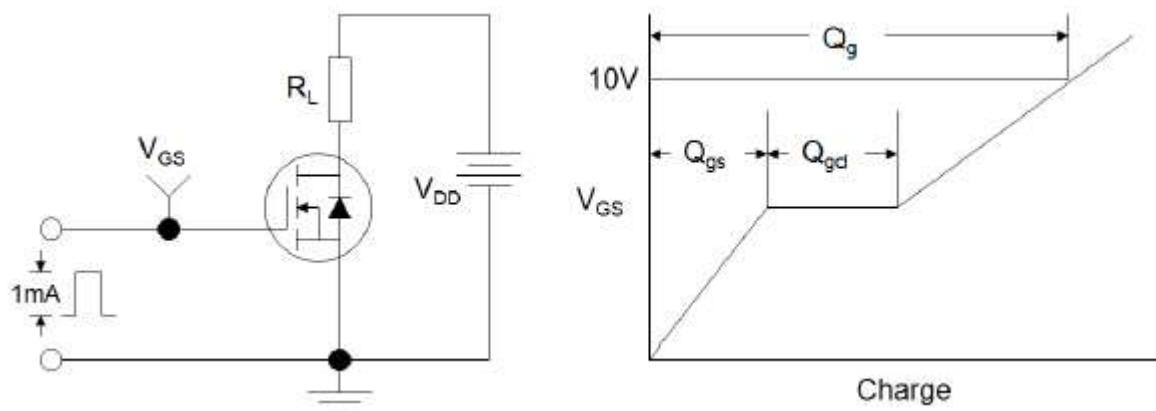


Figure 1: Gate Charge Test Circuit & Waveform

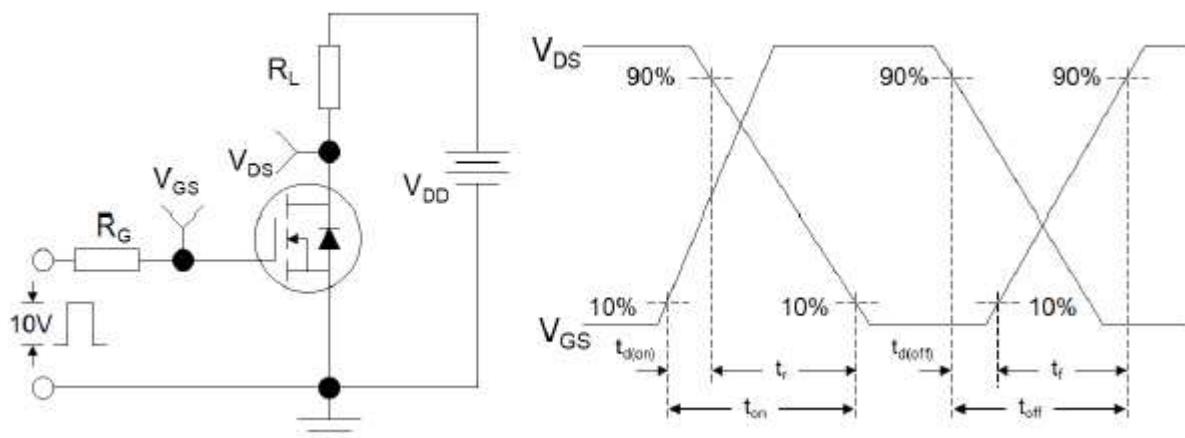


Figure 2: Resistive Switching Test Circuit & Waveforms

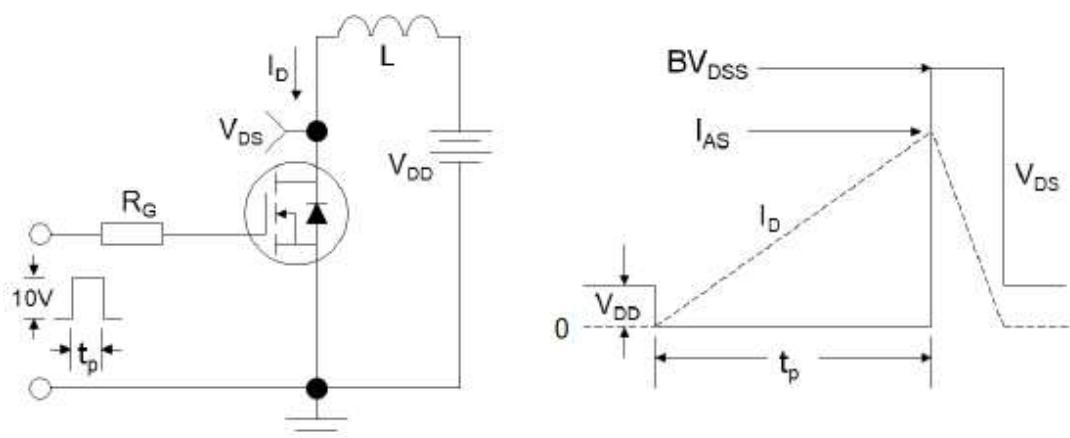
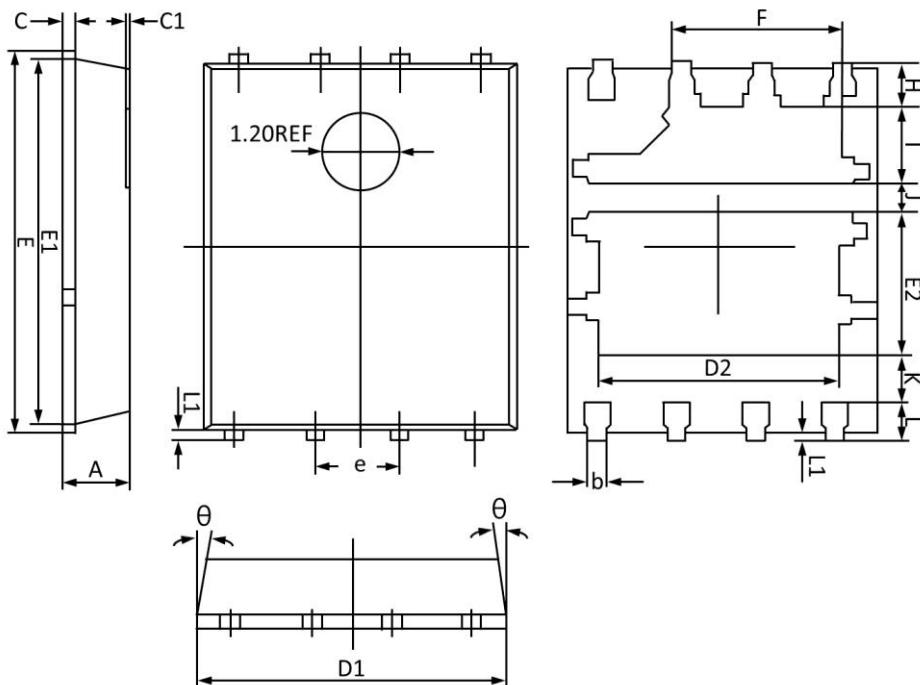


Figure 3: Unclamped Inductive Switching Test Circuit & Waveforms

PDFN5X6-8L Package Information (unit:mm)



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.900	1.100	0.036	0.043
b	0.330	0.510	0.013	0.020
C	0.200	0.300	0.008	0.011
C1	0.040 REF		0.040 REF	
D1	4.800	5.000	0.189	0.196
D2	3.610	3.960	0.143	0.155
E	5.900	6.100	0.233	0.240
E1	5.700	5.800	0.225	0.228
E2	2.020	2.420	0.080	0.095
e	1.270BSC		1.270BSC	
F	2.550	2.900	0.101	0.114
H	0.610	0.810	0.025	0.031
I	1.100	1.300	0.044	0.051
J	0.400	0.600	0.016	0.023
K	0.500	-	0.020	-
L	0.510	0.710	0.020	0.027
L1	0.060	0.200	0.003	0.007
θ	0°	12°	0°	12°